


<b>Search Notes</b>  	<b>Application/Control No.</b>  10817164	<b>Applicant(s)/Patent Under Reexamination</b>  DE ROOIJ ET AL.
	<b>Examiner</b>  Stacy B Chen	<b>Art Unit</b>  1648

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
updated PALM	6/11/08	/SBC/
updated PALM all inventors	1/23/09	/SBC/
updated PALM all inventors; EAST	4/20/09	/SBC/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
USPGPUBs		4/20/09	/SBC/

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